Specifications

Drawing No.	USY1N-H1-15378-00	1/6
Issued Date.	Jul,28,2015	

Messrs: Digi-key

Note: Part Number will be revised in case of specification change.

Product Type	Tuning Fork Crystal			
Series	ST2012SB			
Frequency	32.768 kHz			
Customer Part Number	-			
Customer Specification Number	-			
KYOCERA Part Number	ST2012SB32768H5WZZAP			
Remarks Pb-Free, RoHS Compliant, MSL 1				

Customer Approval

Approval Signature	Approved Date	Approved Date
	Department	Department
	Person in charge	Person in charge

Seller

KYOCERA Crystal Device Corporation (Sales Division) 6 Takeda Tobadono-cho, Fushimi-ku, Kyoto

612-8501 Japan TEL. No. 075-604-3500 FAX. No. 075-604-3501

Manufacturer

KYOCERA Crystal Device Corporation (Crystal Units Division) 5850, Higashine-Koh, Higashine-Shi, Yamagata 999-3701 Japan

TEL. No. 0237-43-5611 FAX. No. 0237-43-5615

Design Department	Quality Assurance	Approved by	Checked by	Issued by
KYOCERA Crystal Device Corporation Crystal Unit Application Engineering Section Crystal Units Division	F.Mukae	T.Soda	A.Muraoka	Y.Nozaki

Drawing No. USY1N-H1-14378-00 2 / 6

Revision History

Rev.No.	Description of revision	Date	Approved by	Checked by	Issued by
0	First Edition	Jul,28,2015	T.Soda	A.Muraoka	Y.Nozaki

1. APPLICATION

This specification sheet is applied to tuning fork crystal "ST2012SB".

2. PART NUMBER

ST2012SB32768H5WZZAP

3. RATINGS

Items	SYMB.	Rating	Unit
Operating Temperature range	Topr	-25~+75	deg. C
Storage Temperature range	Tstg	-40~+85	deg. C

4. CHARACTERISTICS 4-1 ELECTRICAL CHARACTERISTICS

Itom	Sumbol	Electrical Specification				
	Symbol	Condition	Min	Тур.	Max	Unit
Nominal Frequency	fo	Ta = 25 deg. C		32.768		kHz
Frequency Tolerance	df/fo	Ta = 25 deg.C				
Frequency Stability	df/T	Operating Temperature	-250		250	ppm
Aging	df/F	Ta = 25 deg. C 1year				
Load Capacitance	CL			12.5		pF
Equivalent series resistance	R1				75	kΩ
Q-Value	Q		9000			
Motional capacitance	C1		4.8		6.8	fF
Shunt capacitance	Со		0.9		1.7	pF
Turning point	Тр		20		30	deg. C
Secondary temperature Coefficient	к		-4.0			10 ⁻⁸ /°C2
Drive level	DL			0.1	0.5	μW
Insulation resistance (between electrodes)	IR		500			MΩ

4-2 MOISTURE SENSITIVITY LEVEL

Level 1

(TOP VIEW) 2.0±0.1 1.2±0.1 K 2 2 5 A 0.6MAX (1)(2)(3)4-(0.215) (Side View) $\mathbf{\Lambda}$ Λ (Bottom View) 6-(0.1) C0.20 4-(R0.1) I€ \leftarrow 0.80 \rightarrow

5. APPEARANCES, DIMENSION

CONNECTION (TOP VIEW)



UNIT : mm

MARKING

(3.)

- (1.) Identification
- (2.) Date Code (3 Digits)

Load Capacitance

K

Last 1 digit of year and week Code.

(Example) 12.5pF → A

*The font of marking above is for reference purpose.

6. RECOMMENDED LAND PATTERN



Drawing No. USY1N-H1-14378-00 5/6

7. RELIABILITY

Frequency Stability, and ESR Stability, After stressing.

TEST ITEM		Frequency Stability	ESR Stability	Remarks	
		(ppm)			
7.1	High temp. use/storage	± 10			
7.2	Low temp. use/storage	± 10		Ta=25 deg. C	
7.3	Shock	± 20			
7.4	Vibration	± 10	$\pm 5 \text{ K} 2 \text{ IVIAX}$		
7.5	Soldering Heat Resistance reflow	± 10	$01 \pm 30\%$		
7.6	High temp. With humidity	± 10			
7.7	Temperature cycle	± 10			

8. REFLOW PROFILE

Pb-free reflow requirements for soldering heat resistance



Drawing No. USY1N-H1-14378-00 6 / 6

9. Cautions for use

(1) Soldering upon mounting

Characteristics may be affected when Solder paste or conductive glue comes in contact with product lid or surface.

(2) When using mounting machine

Please minimize the shock when using mounting machine to avoid any excess stress to the product.

(3) Conformity of a circuit

We strongly recommend to make sure that Negative resistance (Gain) of IC is designed to be 3 times the ESR (Equivalent Series Resistance) of Crystal unit.

10. Storage conditions

Please store product in below conditions, and use within 6 months. Temperature +18 to +30°C, and Humidity of 20 to 70 % in the packaging condition.

11. Manufacturing location

Kyocera Crystal Device Corporation Shiga Yohkaichi Plant

12. Quality Assurance

To be guaranteed by Kyocera Crystal Device Quality Assurance Division

13. Quality guarantee

When Kyocera Crystal Device Corporation rooted failure occurs within 1 year after its delivery, substitute product will be arranged based on discussion. Quality guarantee of product after 1 year of its delivery will be waivered.

14. Others

In case of any questions or opinions regarding the Specification, please have it in written manner within 45 days after issued date.